## N tice of R f rences Cited

		$\mathcal{U}_{\mathcal{I}}$	
Application/Control No.	Applicant(s)/Pa	tent Under	
09/835,673	Reexamination BUCHALLA ET AL.		
Examiner	Art Unit		
John J. Wilson	3732	Page 1 of 1	

## **U.S. PATENT DOCUMENTS**

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification	
	Α	US-6095810	08-2000	Bianchetti	433/29	Z
	В	US-4498868	02-1985	Schuss	433/29	7
	С	US-4642738	02-1987	Meller	433/29	₹
	D	US-5894620	04-1999	Polaert et al.	433/29	7
	E	US-				]
	F	US-				7
	G	US-				1
	Н	US-			•	1
	1	US-				
	J	US-				1
	К	US-				
	L	US-				
	М	US-				]

## **FOREIGN PATENT DOCUMENTS**

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Country	Name ·	Classification
	N	EP 0113152	07-1994	EPO	Lafond	_
	0					
	Р					
	Q					
	R					
	s					
	Т					

## **NON-PATENT DOCUMENTS**

*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)
	C	- · ·
	٧	
	w	
	х	

\*A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a).) Dates in MM-YYYY format are publication dates. Classifications may be US or foreign.

